S arch Notes

Application/Contr I No.	Applicant(s)/Pat nt under Re xamination	
10/815,445	LEE ET AL.	
Examiner	Art Unit	
Sonny TRINH	2618	

SEARCHED					
Class	Subclass	Date	Examiner		
455	67.11	6/5/2006	ST		
455	67.14	6/5/2006	ST		
455	115.1	6/5/2006	ST		
455	115.2	6/5/2006	ST		
455	226.1	6/5/2006	ST		
455	423	6/5/2006	ST		
455	225	6/5/2006	ST		
455	67.13	6/5/2006	ST		
455	68	6/5/2006	ST		
455	69	6/5/2006	ST		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
See	attached	6/5/2006	ST		
	1				

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
U.S. Patent, EPO, JPO, DERWENT, PG-PUB	6/5/2006	ST
		_